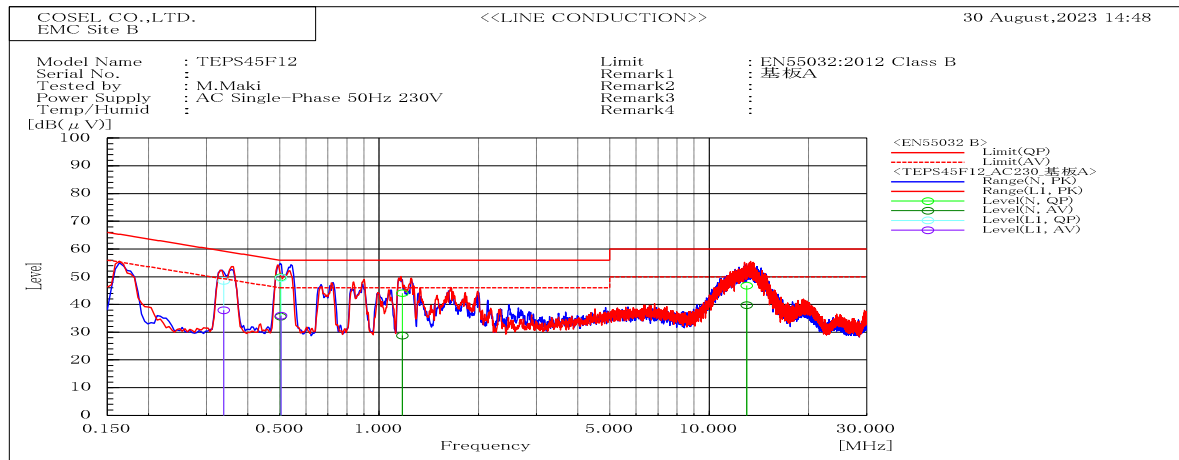
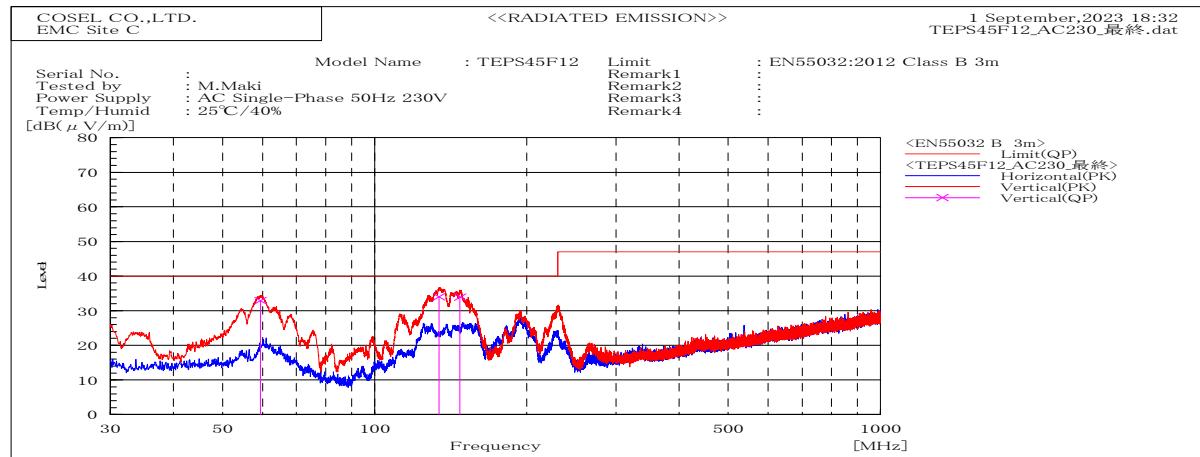


DATA SHEET		Date	12-Oct-23
Model	TEPS45F12	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	M.Maki



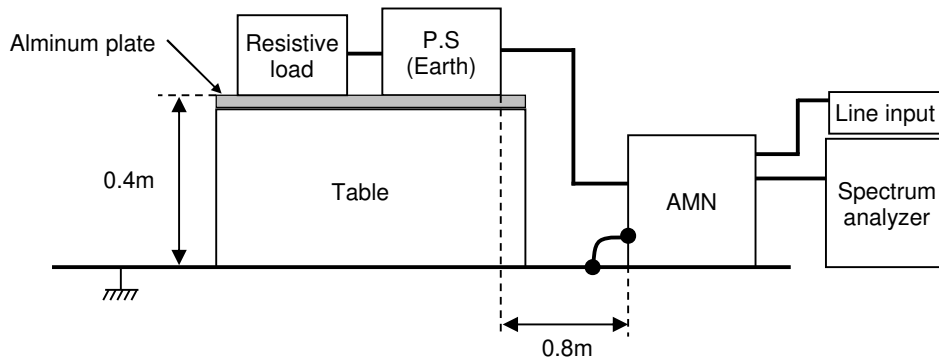
Frequency	Line	Level		Limit		Margin		Pass/Fail	Remark
MHz		dB(μV)		dB(μV)		dB			
		QP	AV	QP	AV	QP	AV		
0.338	L1	48.5	37.9	59.3	49.3	10.8	11.4	Pass	
0.504	L1	49.6	36	56	46	6.4	10	Pass	
0.503	N	49.8	35.6	56	46	6.2	10.4	Pass	
1.176	N	44.1	28.8	56	46	11.9	17.2	Pass	
13.001	N	46.8	39.8	60	50	13.2	10.2	Pass	



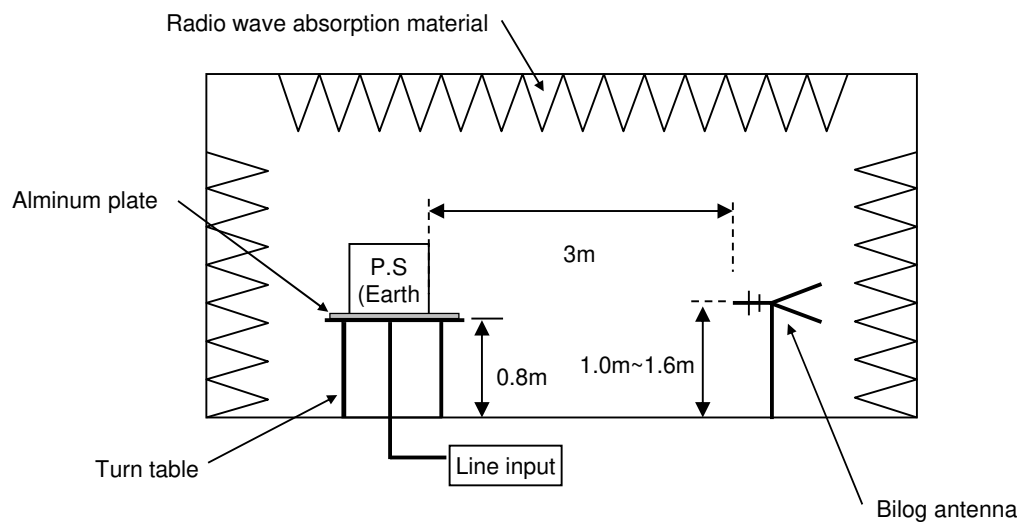
Frequency MHz	Polarization	Stability	Level	Limit	Margin	Pass/Fail	Height cm	Angle deg	Remark
			dB(μV/m) QP	dB(μV/m) QP	dB QP				
59.424	V	Stable	32.9	40	7.1	Pass	100.4	357.8	
133.928	V	Stable	34	40	6	Pass	100.2	30.9	
147.376	V	Stable	33.9	40	6.1	Pass	100.2	55.6	

DATA SHEET		Date	12-Oct-23
Model	Circuit used for measurement	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	M.Maki

1. Line conduction



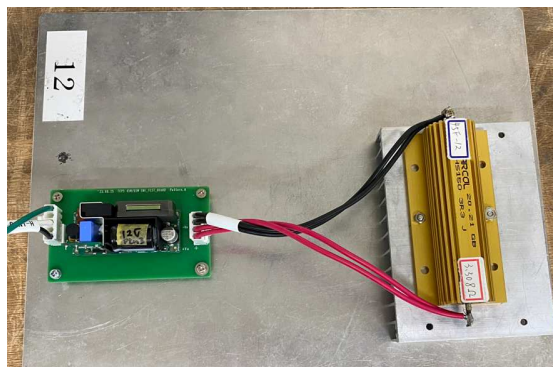
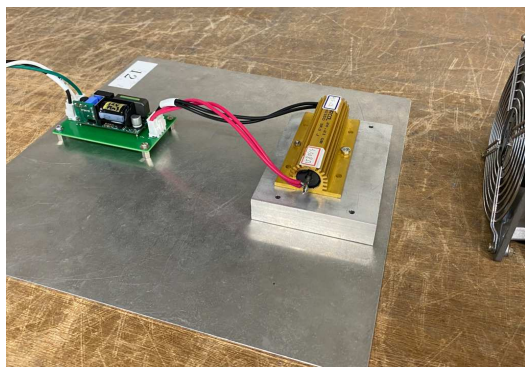
2. Radiated emission



Conditions

Test : EMI
Model Nam: TEPS45F12

1.LINE CONDUCTION



2.RADIATED EMISSION

